



IPW

Docket No.: R2180.0188/P188
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Takamitsu Yamada et al.

Application No.: 10/763,255

Confirmation No.: 7512

Filed: January 26, 2004

Art Unit: 2829

For: SEMICONDUCTOR INTEGRATED
CIRCUIT AND SCAN TEST METHOD
THEREFOR

Examiner: Not Yet Assigned

STATUS INQUIRY

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

It is respectfully requested that the attorney named below be advised of the status of the above-identified application. Please advise us of when we might expect to receive an Office Action from the Patent and Trademark Office.

Dated: November 8, 2005

Respectfully submitted,

By 

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